

| | | | |
|-----------------------------------|---------------------------------------|--|-------------|
| Notice of References Cited | Application/Control No. 09/954,508 | Applicant(s)/Patent Under Reexamination TODOROV ET AL. | |
| | Examiner Tammy T. Nguyen | Art Unit 2144 | Page 1 of 1 |

U.S. PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Name | Classification |
|---|---|--|-----------------|-----------------|----------------|
| | A | US-6,430,598 B1 | 08-2002 | Dorrance et al. | 709/203 |
| | B | US-6,718,550 B1 | 04-2004 | Lim et al. | 710/310 |
| | C | US-6,601,094 B1 | 07-2003 | Mentze et al. | 709/220 |
| | D | US-6,263,330 B1 | 07-2001 | Bessette, Luc | 707/4 |
| | E | US-5,991,820 A | 11-1999 | Dean, Edward A. | 719/312 |
| | F | US-6,480,901 B1 | 11-2002 | Weber et al. | 709/246 |
| | G | US-6,480,597 B1 | 11-2002 | Kult et al. | 379/242 |
| | H | US-6,498,835 B1 | 12-2002 | Skladman et al. | 379/88.12 |
| | I | US- | | | |
| | J | US- | | | |
| | K | US- | | | |
| | L | US- | | | |
| | M | US- | | | |

FOREIGN PATENT DOCUMENTS

| * | | Document Number Country Code-Number-Kind Code | Date MM-YYYY | Country | Name | Classification |
|---|---|--|-----------------|---------|------|----------------|
| | N | | | | | |
| | O | | | | | |
| | P | | | | | |
| | Q | | | | | |
| | R | | | | | |
| | S | | | | | |
| | T | | | | | |

NON-PATENT DOCUMENTS

| * | | Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) |
|---|---|---|
| | U | |
| | V | |
| | W | |
| | X | |

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.